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Thin-film piezoelectric MEMS

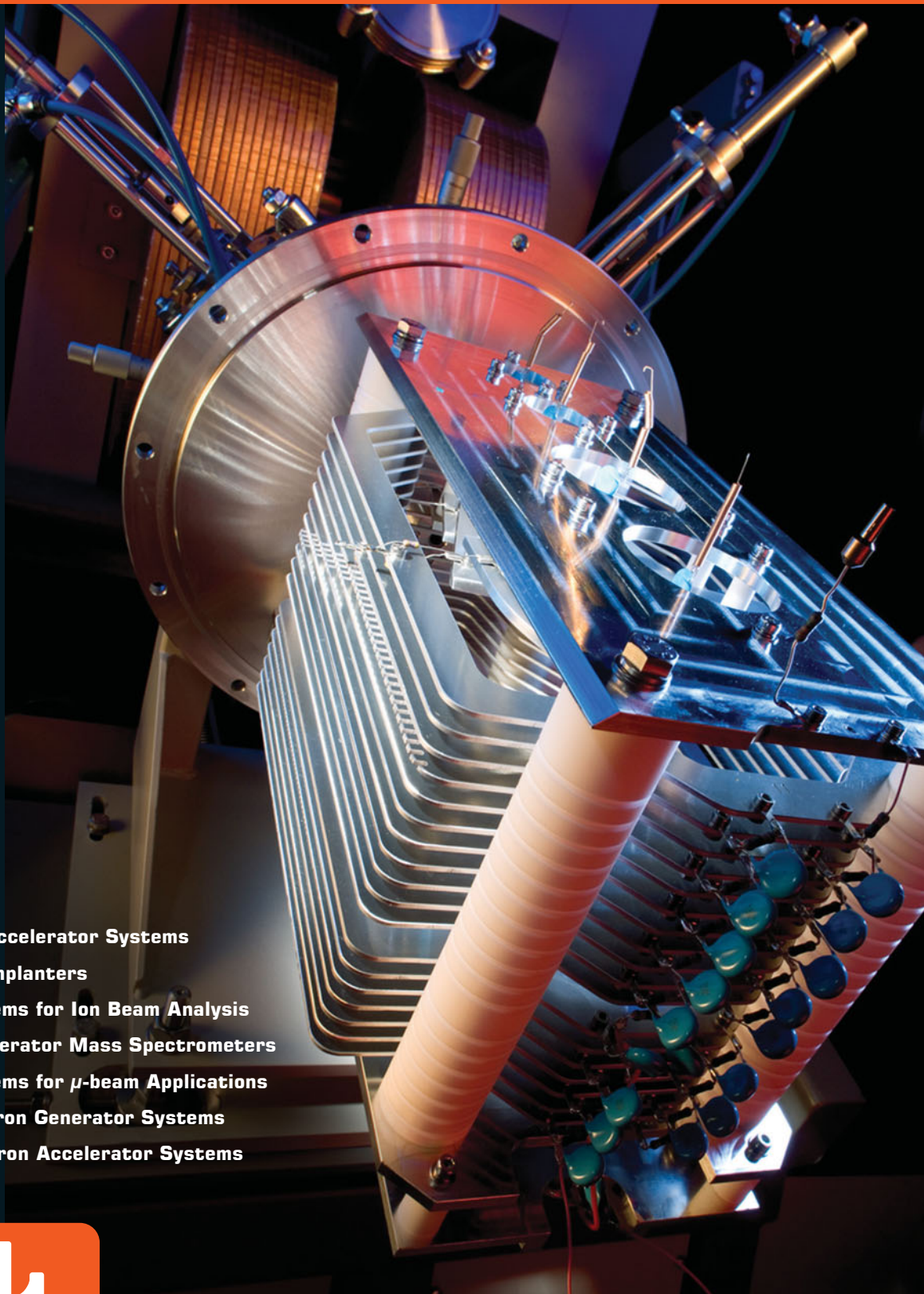


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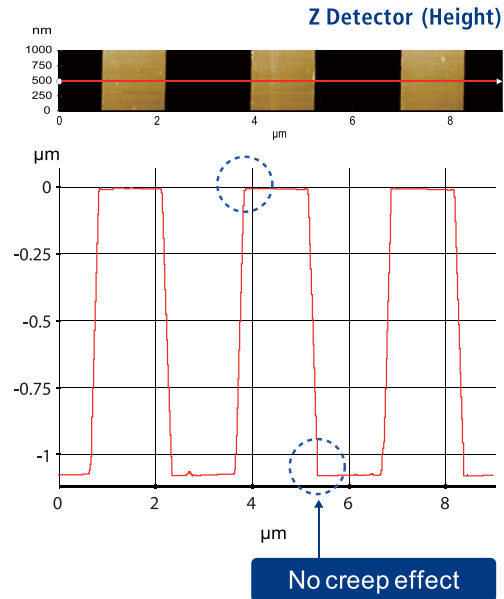
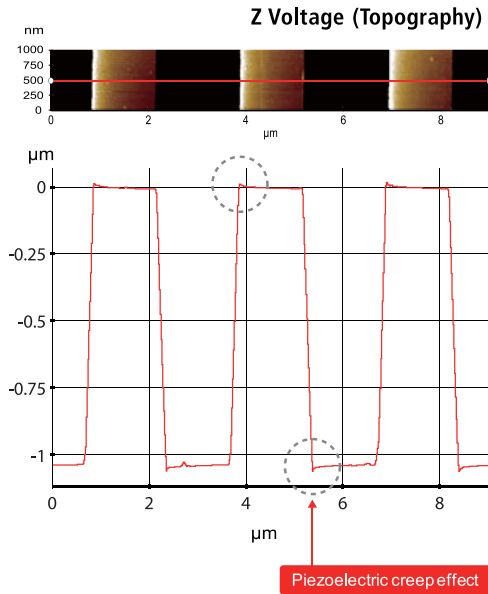


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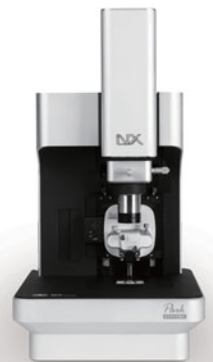
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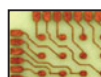


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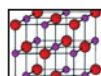
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ON THE COVER



Thin-film piezoelectric MEMS. This issue of *MRS Bulletin* focuses on some of the challenges microelectromechanical systems (MEMS) face as they move to smaller sizes and increased integration density, while requiring fast response and large motions. Advances in the field are being driven by and are prompting advances in heterostructure design and theoretical investigations. On the cover is a notional millimeter-scale robotic system based on PZT MEMS and highly integrated microelectronics. Green regions indicate PZT MEMS actuators, and the stacked "chips" on the body segments represent other required microelectronic subsystems. The robot is a hexapod (six-legged)-based flight-capable design. See the technical theme that begins on page 1007.

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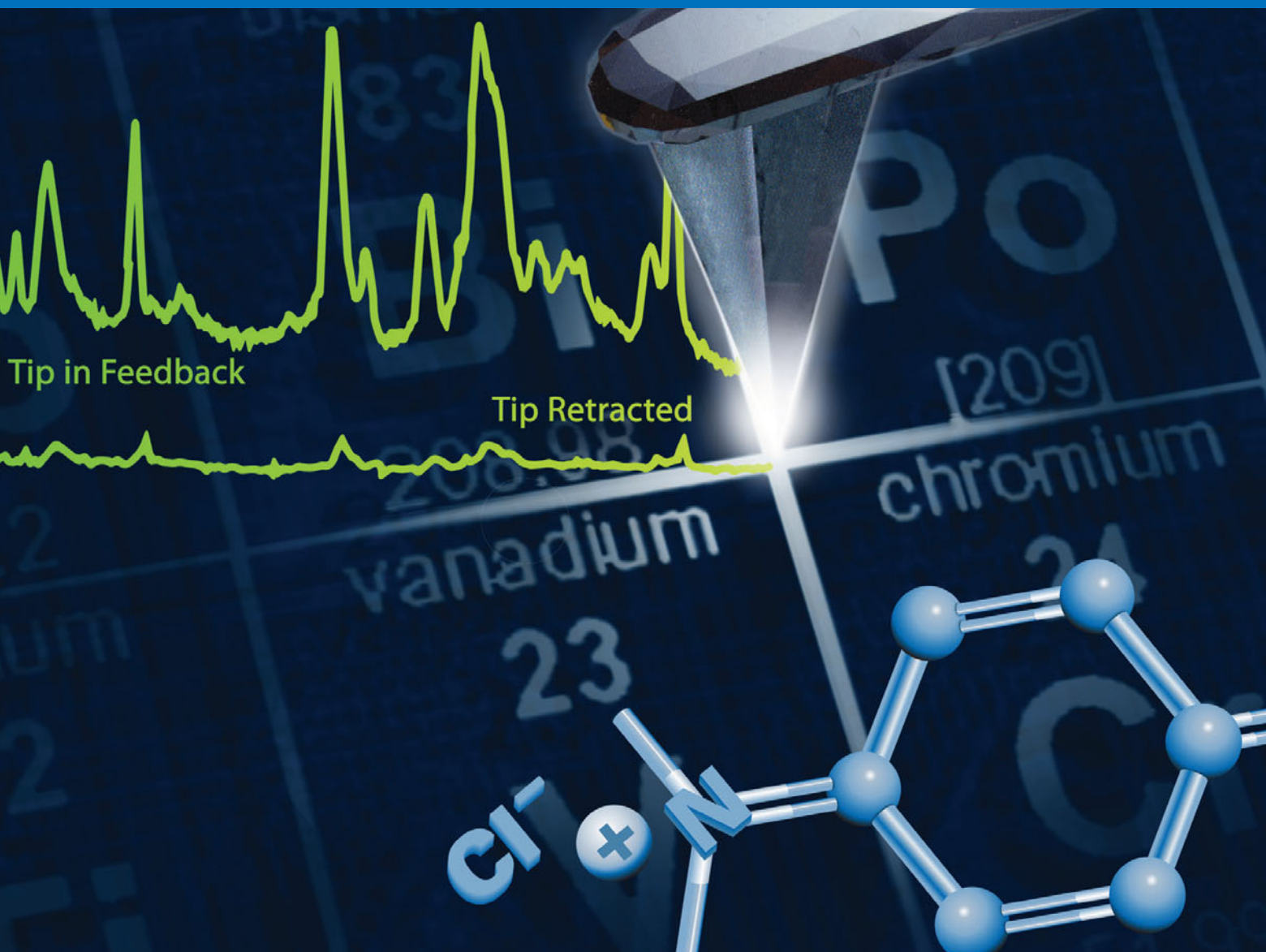
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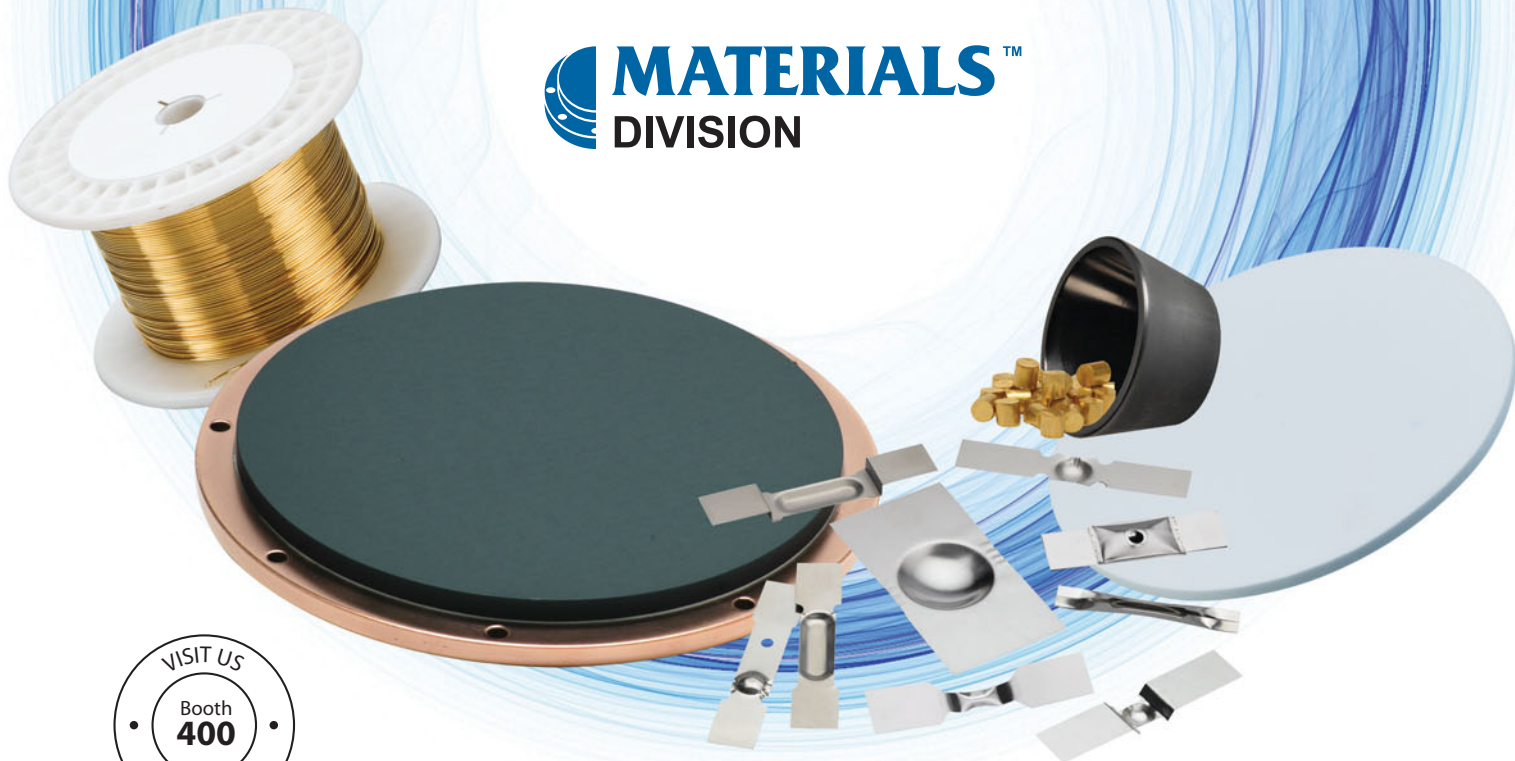
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